



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Matthias SLODOWSKI
Title: APPARATUS AND METHOD FOR THIN-LAYER
METROLOGY
Appl. No.: 10/777,162
Filing Date: 2/13/2004
Examiner: Gordon J. Stock, Jr.
Art Unit: 2877
Confirmation No.: 5100

AMENDMENT AND REPLY ACCOMPANYING RCE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This communication is responsive to the Advisory Action dated October 2, 2007, and the final Office Action dated June 13, 2007, concerning the above-referenced patent application.

This communication is being filed concurrently with a Request for Continued Examination (RCE).

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this document.

Remarks/Arguments begin on page 6 of this document.

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